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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

DESC FORM 193

MAY 86

1. SCOPE				
1.1 Scop 1.2.1 of MI devices".	e. This drawing do T-STD-883, "Provis	escribes device req lons for the use of	uirements for cla MIL-STD-883 in c	ss B microcircuits in accordance with onjunction with compliant non-JAN
1.2 Part	number. The comp	lete part number sh	all be as shown i	n the following example:
	5962-87691	01	<u>E</u>	<u> </u>
	Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510
1.2.1 <u>De</u>	vice type. The de	vice type shall ide	entify the circuit	function as follows:
	Device type	Generic number	<u>Circuit f</u>	unction
	01	54AC151	8-Input m	ultiplexer
1.2.2 Ca and as foll		case outlines shall	be as designated	in appendix C of MIL-M-38510,
	Outline le	tter		Case outline -
	E F 2		F-5 (16-Lead	1/4" x 7/8") dual-in-line package 1/4" x 3/8") flat-package nal .350" x .350") square tier
1.3 Absol	lute maximum rating	<u>s</u> .		

Supply voltage range 1/	-0.5 Y dc to +6.0 Y dc
DC input voltage 1/	-0.5 V dc to V _{CC} +0.5 V dc -0.5 V dc to V _{CC} +0.5 V dc
DC output voltage 1/	-U.5 Y QC TO YOU TU.5 Y QC
Clamp diode current	± 20 mA
no author current (par nin)	± 50 mA
DC Voc or GND current (per pin)	* 100 mA
Storage temperature range	-65°C to 150°C
Maydeum noway diccination Do	500 msw
Lead temperature (soldering, 10 seconds)	+245 C
Thermal resistance, junction-to-case (0JC) Cases E and F	
Cases E and F	See MIL-M-38510, appendix C
Case 2	60°C/W <u>2/</u> +175°C
Junction temperature (T_J) 3/	+175°C

1/ Unless otherwise specified, all voltages are referenced to GND.

Z/ When a thermal resistance value is included in MIL-M-38510, appendix C, it shall supersede the

value stated herein.

3/ Maximum junction temperature shall not be exceeded except for allowable short duration burn-in screening conditions per method 5004 of MIL-STD-883.

MILITARY DRAWING	SIZE A	67268	DWG NO 59	62-87691	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV		PAGE	2

1.4 Recommended operating conditions.
Supply voltage (V _{CC}) 4/
VCC = 3.0 V 0 to 88 ns (10-90%, 20ns/V)
2. APPLICABLE DOCUMENTS
2.1 <u>Government specification and standard</u> . Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.
SPECIFICATION
MILITARY
MIL-M-38510 - Microcircuits, General Specification for.
STANDARD
MILITARY
MIL-STD-883 - Test Methods and Procedures for Microelectronics.
(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)
2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
3. REQUIREMENTS
3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
3.2 <u>Design, construction, and physical dimensions</u> . The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
3.2.1 Terminal connections and logic diagram. The terminal connections and logic diagram shall be as specified on figure 1.
3.2.2 Truth table. The truth table shall be as specified on figure 2.
3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
$\frac{47}{2}$ Operation from 2.0 V dc to 3.0 V dc is provided for compatibility with data retention and battery backup systems. Data retention implies no input transitions and no stored data loss with the following conditions: $V_{IH} \geq 70\%$ V _{CC} , $V_{IL} \leq 30\%$ V _{CC} , $V_{OH} \geq 70\%$ V _{CC} at -20 μA, $V_{OL} \leq 30\%$ V _{CC} at 20 μA

MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO

SIZE
CODE IDENT. NO.
DWG NO.
5962-87691

REV
PAGE 3

Test	Symbol		-55°C <	ndition T _C ≤ +	s 125°C	Group A subgroups	Limi	1	Unit
ligh level output voltage	VOH	VIN =	V _{IH} or V -50 μA	IL	V _{CC} = 3.0 V	1,2,3	2.9		٧
<u>1</u> /	1			1	V _{CC} = 4.5 V	†	4.4	1	
		1		ţ	V _{CC} = 5.5 V	†	5.4	1	
		VIN	= V _{IH} or = -4 mA	V _{IL}	V _{CC} = 3.0 V		2.4		
	1	AIN	= V _{IH} or = -24 mA	VIL	V _{CC} = 4.5 V	†	3.7		
	!	1		1	V _{CC} = 5.5 V		4.7		
	1	IOH	= V _{IH} or = -50 mA	VIL	V _{CC} = 5.5 V	1	3.85		
ow level output voltage	VOL	VIN	= V _{IH} or = 50 μA	٧ _{IL}	V _{CC} = 3.0 V	1,2,3		0.1	٧
<u>1</u> /		1		†	V _{CC} = 4.5 V	† -		0.1	
				Ť	V _{CC} = 5.5 V	·	1	0.1	
		1	= V _{IH} or = 12 mA	1	V _{CC} = 3.0 V	Ţ		0.5	
	İ	VIN	= V _{IH} or = 24 mA	VIL	$V_{CC} = 4.5 \text{ V}$	İ		0.5	
		1		1	$V_{CC} = 5.5 \text{ V}$	<u> </u>	1	0.5	
		IOF	= V _{IH} or = 50 mA	AIT	V _{CC} = 5.5 V		1	1.65	
High level input voltage	AIH		-		V _{CC} = 3.0 V		2.1		٧
<u>2</u> /	1	!		1	V _{CC} = 4.5 V	1	3.15	1	
	1			+	V _{CC} = 5.5 V	†	3.85	1 1	
Low level input voltage	VIL				V _{CC} = 3.0 V			0.9	٧
<u>2</u> /				1	V _{CC} = 4.5 V	†	 	1.35	
	1			†	V _{CC} = 5.5 V	†	 	1.65	
ee footnotes at end of ta	ble.			<u>-\</u>					
MILITARY DRA	WINC	}	SIZE		7268	DWG NO.	52-8769)1	
DEFENSE ELECTRONICS SU DAYTON, OHIO		ITER	- 		REV	1	PAGE		

TARL	E I. Ele	ctrica	al perform	ance cl	naracteristics	- Continu	ed.		
	T		· · · · · ·	nditio	ne	Group A	Lim	its	Unit
Test	Symbol	1 1	-55°C <u>≺</u>	^T C <u>≤</u> +	125°C	subgroups 	Min	Max	
Input leakage current	IIL	 VM =	0.0 V		V _{CC} = 5.5 V	1,2,3		-1.0	μА
	ITIH	 VM =	5.5 V	1		l l	1 1	1.0	
Quiescent current	1 CCH	AIN	5.5 V = VCC or (= 5.5 V	GND		1,2,3	l	160	μА
	ICCL						1	160	
Input capacitance	CIN	see	4.3.1c			4		8.0	pF
Power dissipation 3/	ICPD	see	4.3.1c			4	 	135	pF
capacitance Functional tests		repe	ed at V _{CC} eated at V 4.3.1d	= 3.0 cc = 5.	V and .5 V	7,8	1		
Propagation delay time	 t _{PHL}	T	. 25°C		V _{CC} = 3.0 V	9	1.0	15.0	ns
High-to-Low Low-to-High	1	Ci =	: 50 pF : 500Ω		$V_{CC} = 4.5 \text{ V}$	}	1.0	111.0	
LOW-CO-III 9II	i Itou	See	figure 3		V _{CC} = 3.0 V	Ì	1.0	13.5	
	tpLH	ļ			V _{CC} = 4.5 V	ì	ĺ	i 10.0	
	<u> </u>				*CC = 4.5 *	<u> </u>	1		
In to Z or Z	 t _{PHL}	T _C =	= -55°C/12	5°C	V _{CC} = 3.0 V	10,11	1.0	18.0	
<u>4</u> /	1	C _L =	= 50 pF = 500Ω		$V_{CC} = 4.5 \text{ V}$	_! -	1.0	13.0	
<u> </u>	 tpLH	See	figure 3		V _{CC} = 3.0 V	 - 	1.0	116.0	
	I I	į		!	V _{CC} = 4.5 V	 	1.0	112.0	
Propagation delay time	tpHL	T _C =	= 25°C = 50 pF		V _{CC} = 3.0 V	9	1.0	18.0	
High-to-Low Low-to-High	1	iR _i =	ະ 500Ω		V _{CC} = 4.5 V	-[1.0	13.0	<u> </u>
-	 tpLH	See	ee figure 3		V _{CC} = 3.0 V	\	1.0	118.0	! !
		1			V _{CC} = 4.5 V	ľ	1.0	13.0	
Sn to Z or Z	tpHL	T _C =	= -55°C/12	.5°C	V _{CC} = 3.0 V	10,11	1.0	22.0	
4/	1	l Ci :	= 50 pF = 500Ω		$\frac{1}{V_{CC}} = 4.5 \text{ V}$	- <mark>1</mark>	1.0	115.5	i
<u> </u>	İ.	See	figure 3		V _{CC} = 3.0 V	ı	1.0	122.0	[]
	tpLH	į			V _{CC} = 4.5 V		1	15.5	
See footnotes at end of ta	ble.	1			<u> </u>	!		<u> </u>	+*
MILITARY DRA	WING	:	SIZE		TOCO	DWG NO.			
DEFENSE ELECTRONICS SU			Α	ס	7268	596	2-8769	1	
DAYTON, OHIO					REV		PAGE	5	

Test	Symbol	Conditions -55°C < T _C < +12	5°C	Group A subgroups	Lim	Unit	
1630		-33 0 2 10 2 11] 	Min	Max		
Propagation delay time	tpHL	T _C = 25°C C _L = 50 pF	V _{CC} = 3.0 V	9	1.0	13.0	ns
High-to-Low Low-to-High	1	CL = 30 pr RL = 500Ω See figure 3	V _{CC} = 4.5 V	i i	1.0	10.0	
•	tpLH	T See Figure 3	$V_{CC} = 3.0 \text{ V}$	1	1.0	13.0	
) 	V _{CC} = 4.5 V	i i	1.0	10.0	
En to Z or Z	tpHL	T _C = -55°C/125°C C _L = 50 pF	V _{CC} = 3.0 V	10,11	1.0	15.5	
<u>4</u> /		! KL = 500Ω	V _{CC} = 4.5 V	-[1.0	12.0	
	tpLH	See figure 3 	$V_{CC} = 3.0 \text{ V}$		1.0	15.5	
		ļ ļ	V _{CC} = 4.5 V	1	1.0	12.0	

 V_{OH} and V_{OL} tests will be tested at V_{CC} = 3.0 V and V_{CC} = 4.5 V. All other voltages are guaranteed, but not tested. Limits shown apply to operation at V_{CC} = 3.3 V ± 0.3 V and V_{CC} = 5.0 V ± 0.5 V. Transmission driving tests are performed at V_{CC} = 5.5 V with a 2 ms duration maximum.

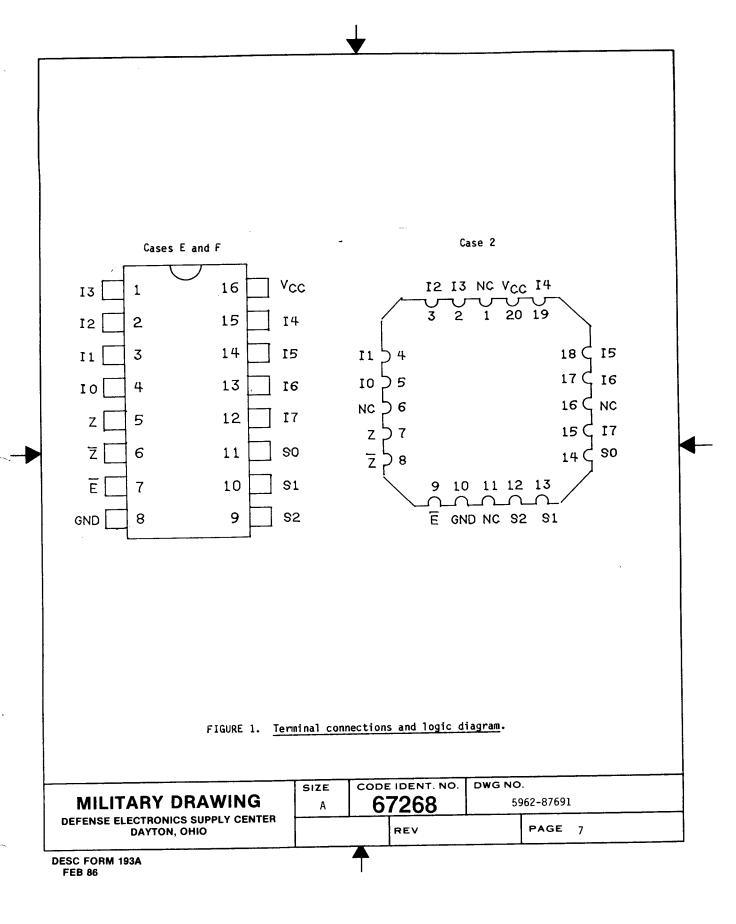
Quration maximum. V_{IH} and V_{IL} tests are guaranteed by the V_{OH} and V_{OL} tests. Power dissipation capacitance (C_{PD}), determines the dynamic power consumption, PD = (C_{PD} + C_{L}) V_{CC} f + I_{CC} V_{CC} , and the dynamic current consumption (IS) is, IS = (C_{PD} + C_{L}) V_{CC} f + I_{CC} . AC limits at 5.5 V V_{CC} are equal to limits at 4.5 V V_{CC} and guaranteed by testing at 4.5 V V_{CC} . Minimum ac guaranteed for 5.5 V V_{CC} by guardbanding 4.5 V V_{CC} limits to 1.5 ns minimum.

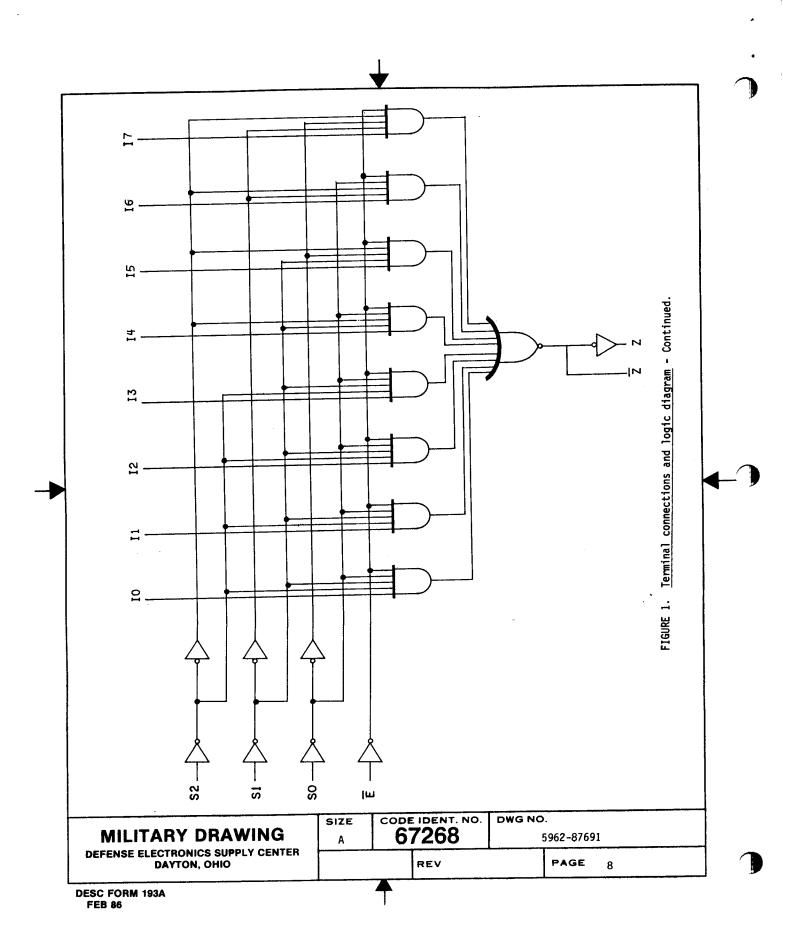
3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

MILITARY DRAWING	SIZE A	67268	DWG NO. 5962-87691		
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE	6	



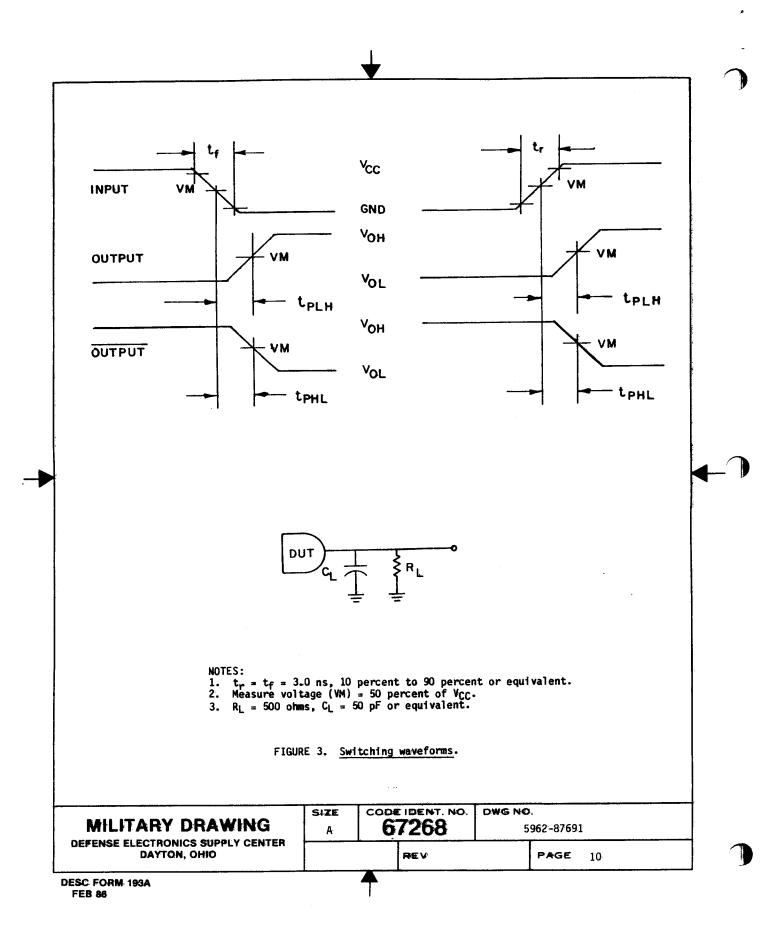


	Inp	outs		Outputs				
Ē	S2	S1	S0	7	Z			
Н	Х	Х	Х	Н	L			
 L	L	L	L	10	10			
L	! ! L	L	i H	ĪĪ	11			
 L	L	Н	l L	Ī2	12			
l I L	 L	 H	! н	13	13			
l ļ L	 H	l ! L	! ! L	14	14			
 L	!] H	l L	I I Н	15	15			
 L	 H	 ! н	 L	16	16			
 L 	 H 	 H 	 H 	 <u>17</u> 	17			

H = High voltage level L = Low voltage level X = Immaterial

FIGURE 2. Truth table.

MILITARY DRAWING	SIZE	67268	DWG NO. 5962-876	591
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE	9



- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125$ °C, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-SID-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 4 (C_{IN} and C_{PD} measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance.
 - d. Subgroup 7 and 8 tests sufficient to verify the truth table.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125$ °C, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

	SIZE	CODE IDENT. NO.	DWG NO.	
MILITARY DRAWING	A	67268	5962-87691	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE	11

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)		
Interim electrical parameters (method 5004)			
Final electrical test parameters (method 5004)	1*,2,3,7,8,9		
Group A test requirements (method 5005) 	1,2,3,7,8,9 10,11		
Groups C and D end-point electrical parameters (method 5005)	1,2,3		
Additional electrical subgroups for group C periodic inspections			

^{*}PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

- 6.2 Replaceability. Replaceability is determined as follows:
 - a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/76201B--.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

MILITARY DRAWING	SIZE A	67268	DWG NO. 5962		
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	P	PAGE	12

6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /	Replacement military specification part number
5962-8769101EX	07263	54AC151 DMQB	M38510/76201BEX
5962-8769101FX	07263	54AC151 FMQB	M38510/76201BFX
5962-87691012X	07263	54AC151 LMQB	M38510/76201B2X

 $\frac{1}{this}$ number may not satisfy the performance requirements of this drawing.

Vendor CAGE number 07263 Vendor name and address

Fairchild Semiconductor 333 Western Ave. So. Portland, ME 04106

DWG NO.

5962-87691

PAGE

13

MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO

SIZE
CODE IDENT. NO.
67268

REV